

Notice of References Cited

Application/Control No.
09/914,744

Applicant(s)/Patent Under
Reexamination
YOSHIDA ET AL.

Examiner

C. Melissa Koslow

Art Unit

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Page 1 of 1

U.S. PATENT DOCUMENTS

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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
*	U	Han et al., "Soft Magnetic Properties of Fe-(Si3N4, Al2O3) Thin Films", IEEE Journal, Vol. 32, No. 5, pp. 4490-4501, 9/96.
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